

**Search Notes**

Application/Control No.

10/626,845

Examiner

Brian L. Albertalli

Applicant(s)/Patent under  
Reexamination

ABSAR ET AL.

Art Unit

2626

**SEARCHED**

| Class | Subclass | Date | Examiner |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE      | EXMR |
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| EAST Search (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout | 2/28/2007 | BA   |
| IEEE Search - Search Terms: spline, envelope, transient, parametric                            | 2/28/2007 | BA   |
| ACM Search - Search Terms: spline, envelope, transient, parametric                             | 2/28/2007 | BA   |
| INSPEC Search - Search Terms: spline, envelope, transient, parametric                          | 2/28/2007 | BA   |
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